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L2	15596	(707/1,2,3,10,100,101,102).CCLS.	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 08:49
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L6	128	5 and @ad<"20011231"	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:04
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L27	37	23 and star	US-PGPUB; USPAT; EPO	OR	OFF	2004/12/02 09:10

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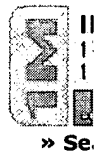
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1 **Efficient processing of outer joins and aggregate junctions**
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